# 4 kb Microwire Serial CMOS EEPROM

## Description

The CAT93C66 is a 4 kb CMOS Serial EEPROM device which is organized as either 256 registers of 16 bits (ORG pin at  $V_{CC}$ ) or 512 registers of 8 bits (ORG pin at GND). Each register can be written (or read) serially by using the DI (or DO) pin. The CAT93C66 features sequential read and self-timed internal write with auto-clear. On-chip Power-On Reset circuitry protects the internal logic against powering up in the wrong state.

## Features

- High Speed Operation: 2 MHz
- 1.8 V to 5.5 V Supply Voltage Range
- Selectable x8 or x16 Memory Organization
- Sequential Read
- Software Write Protection
- Power-up Inadvertent Write Protection
- Low Power CMOS Technology
- 1,000,000 Program/Erase Cycles
- 100 Year Data Retention
- Industrial and Extended Temperature Ranges
- 8-lead PDIP, SOIC, TSSOP, 6-lead SOT-23 and 8-pad TDFN Packages
- These Devices are Pb–Free, Halogen Free/BFR Free, and RoHS Compliant

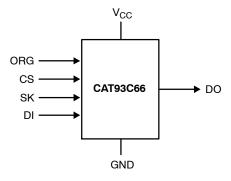


Figure 1. Functional Symbol

**Note:** When the ORG pin is connected to  $V_{CC}$ , the x16 organization is selected. When it is connected to ground, the x8 organization is selected. If the ORG pin is left unconnected, then an internal pull-up device will select the x16 organization.



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SOIC-8 V, W SUFFIX CASE 751BD

TDFN-8 VP2 SUFFIX CASE 511AK



PDIP-8 L SUFFIX CASE 646AA

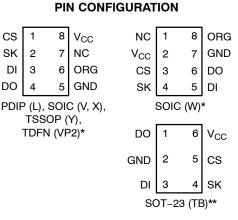
TSSOP-8 Y SUFFIX CASE 948AL





SOIC-8 X SUFFIX CASE 751BE

SOT23-6 TB SUFFIX CASE 527AJ



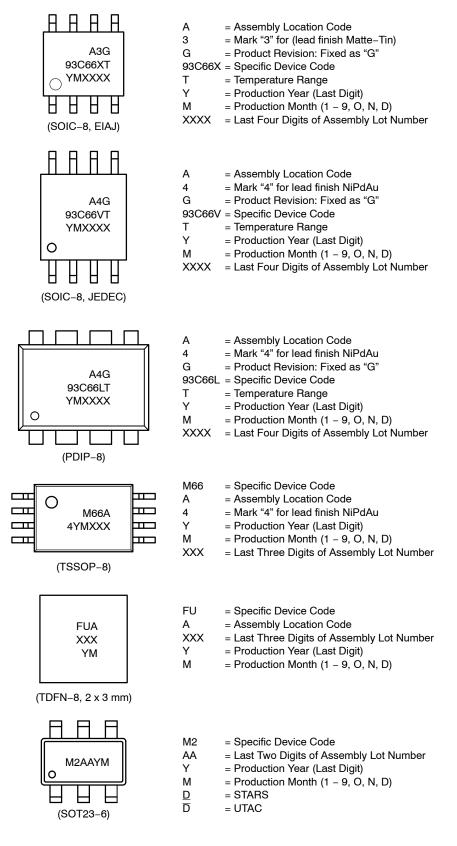
\* SOIC (W) rotated pin-out package is not recommended for new designs

\*\* CAT93C66 available in SOT-23 6-pin for x8 Organization

# **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 15 of this data sheet.

### MARKING DIAGRAMS



## Table 1. PIN FUNCTION

Pin Name	Function	Pin Name	Function
CS	Chip Select	V <sub>CC</sub>	Power Supply
SK	Clock Input	GND	Ground
DI	Serial Data Input	ORG	Memory Organization
DO	Serial Data Output	NC	No Connection

#### Table 2. ABSOLUTE MAXIMUM RATINGS

Parameters	Ratings	Units
Storage Temperature	–65 to +150	°C
Voltage on Any Pin with Respect to Ground (Note 1)	–0.5 to +6.5	V

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. The DC input voltage on any pin should not be lower than -0.5 V or higher than V<sub>CC</sub> + 0.5 V. During transitions, the voltage on any pin may undershoot to no less than -1.5 V or overshoot to no more than V<sub>CC</sub> + 1.5 V, for periods of less than 20 ns.

## Table 3. RELIABILITY CHARACTERISTICS (Note 2)

Symbol	Parameter	Min	Units
N <sub>END</sub> (Note 3)	Endurance	1,000,000	Program / Erase Cycles
T <sub>DR</sub>	Data Retention	100	Years

2. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC–Q100 and JEDEC test methods.

3. Block Mode,  $V_{CC} = 5 V$ ,  $25^{\circ}C$ .

# Table 4. D.C. OPERATING CHARACTERISTICS

 $(V_{CC} = +1.8 \text{ V to } +5.5 \text{ V}, T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C} \text{ unless otherwise specified.})$ 

Symbol	Parameter	Test Condit	tions	Min	Max	Units
I <sub>CC1</sub>	Power Supply Current (Write)	f <sub>SK</sub> = 1 MHz, V <sub>CC</sub> = 5.0 V	$f_{SK}$ = 1 MHz, $V_{CC}$ = 5.0 V			mA
I <sub>CC2</sub>	Power Supply Current (Read)	f <sub>SK</sub> = 1 MHz, V <sub>CC</sub> = 5.0 V			500	μΑ
I <sub>SB1</sub>	Power Supply Current	$V_{IN} = GND \text{ or } V_{CC},$	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$		2	μΑ
	(Standby) (x8 Mode)	CS = GND ORG = GND	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		4	
I <sub>SB2</sub>	Power Supply Current	$V_{IN} = GND \text{ or } V_{CC}, CS = GND$			1	μΑ
	(Standby) (x16 Mode)	ORG = Float or V <sub>CC</sub>	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		2	
ILI	Input Leakage Current	$V_{IN} = GND$ to $V_{CC}$	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$		1	μΑ
			$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		2	
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = GND$ to $V_{CC}$ ,	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$		1	μΑ
		CS = GND	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		2	
V <sub>IL1</sub>	Input Low Voltage	$4.5~\textrm{V} \leq \textrm{V}_{\textrm{CC}} < 5.5~\textrm{V}$	•	-0.1	0.8	V
V <sub>IH1</sub>	Input High Voltage	$4.5~\textrm{V} \leq \textrm{V}_{\textrm{CC}} < 5.5~\textrm{V}$		2	V <sub>CC</sub> + 1	V
V <sub>IL2</sub>	Input Low Voltage	$1.8~\text{V} \leq \text{V}_{\text{CC}} < 4.5~\text{V}$		0	V <sub>CC</sub> x 0.2	V
V <sub>IH2</sub>	Input High Voltage	$1.8~\text{V} \leq \text{V}_{\text{CC}} < 4.5~\text{V}$		V <sub>CC</sub> x 0.7	V <sub>CC</sub> + 1	V
V <sub>OL1</sub>	Output Low Voltage	$4.5~V \leq V_{CC} < 5.5~V,~I_{OL}$ = 2.1 mA			0.4	V
V <sub>OH1</sub>	Output High Voltage	4.5 V $\leq$ V_{CC} < 5.5 V, I_{OH} = –400 $\mu A$		2.4		V
V <sub>OL2</sub>	Output Low Voltage	1.8 V $\leq$ V <sub>CC</sub> < 4.5 V, I <sub>OL</sub> = 1 mA			0.2	V
V <sub>OH2</sub>	Output High Voltage	$1.8 \text{ V} \le \text{V}_{\text{CC}} < 4.5 \text{ V}, \text{ I}_{\text{OH}} = -100$	μΑ	V <sub>CC</sub> – 0.2		V

## Table 5. PIN CAPACITANCE ( $T_A = 25^{\circ}C$ , f = 1.0 MHz, $V_{CC} = +5.0$ V)

Symbol	Test	Conditions	Min	Тур	Max	Units
C <sub>OUT</sub> (Note 4)	Output Capacitance (DO)	V <sub>OUT</sub> = 0 V			5	pF
C <sub>IN</sub> (Note 4)	Input Capacitance (CS, SK, DI, ORG)	V <sub>IN</sub> = 0 V			5	pF

4. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC–Q100 and JEDEC test methods.

## Table 6. A.C. CHARACTERISTICS

(V<sub>CC</sub> = +1.8 V to +5.5 V,  $T_A$  = -40°C to +125°C, unless otherwise specified.) (Note 5)

		Lin	nits	
Symbol	Parameter	Min	Max	Units
t <sub>CSS</sub>	CS Setup Time	50		ns
t <sub>CSH</sub>	CS Hold Time	0		ns
t <sub>DIS</sub>	DI Setup Time	100		ns
t <sub>DIH</sub>	DI Hold Time	100		ns
t <sub>PD1</sub>	Output Delay to 1		0.25	μs
t <sub>PD0</sub>	Output Delay to 0		0.25	μs
t <sub>HZ</sub> (Note 6)	Output Delay to High-Z		100	ns
t <sub>EW</sub>	Program/Erase Pulse Width		5	ms
<sup>t</sup> CSMIN	Minimum CS Low Time	0.25		μs
t <sub>SKHI</sub>	Minimum SK High Time	0.25		μs
t <sub>SKLOW</sub>	Minimum SK Low Time	0.25		μs
t <sub>SV</sub>	Output Delay to Status Valid		0.25	μs
SK <sub>MAX</sub>	Maximum Clock Frequency	DC	2000	kHz

5. Test conditions according to "A.C. Test Conditions" table.

6. These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.

#### Table 7. POWER-UP TIMING (Notes 7, 8)

Symbol	Parameter	Max	Units
t <sub>PUR</sub>	Power-up to Read Operation	1	ms
t <sub>PUW</sub>	Power-up to Write Operation	1	ms

 These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.

8. t<sub>PUR</sub> and t<sub>PUW</sub> are the delays required from the time V<sub>CC</sub> is stable until the specified operation can be initiated.

Table 6. A.C. TEST CONDITION						
Input Rise and Fall Times	≤ 50 ns					
Input Pulse Voltages	0.4 V to 2.4 V	$4.5~V \leq V_{CC} \leq 5.5~V$				
Timing Reference Voltages	0.8 V, 2.0 V	$4.5~V \leq V_{CC} \leq 5.5~V$				
Input Pulse Voltages	0.2 $V_{CC}$ to 0.7 $V_{CC}$	$1.8~V \leq V_{CC} \leq 4.5~V$				
Timing Reference Voltages	0.5 V <sub>CC</sub>	$1.8~V \leq V_{CC} \leq 4.5~V$				
Output Load	Current Source I <sub>OLmax</sub> /I <sub>OHmax</sub> ; CL = 100 pF					

#### Table 8. A.C. TEST CONDITIONS

## **Device Operation**

The CAT93C66 is a 4096-bit nonvolatile memory intended for use with industry standard microprocessors. The CAT93C66 can be organized as either registers of 16 bits or 8 bits. When organized as X16, seven 11-bit instructions control the reading, writing and erase operations of the device. When organized as X8, seven 12-bit instructions control the reading, writing and erase operations of the device. The CAT93C66 operates on a single power supply and will generate on chip, the high voltage required during any write operation.

Instructions, addresses, and write data are clocked into the DI pin on the rising edge of the clock (SK). The DO pin is normally in a high impedance state except when reading data from the device, or when checking the ready/busy status after a write operation. The serial communication protocol follows the timing shown in Figure 2.

The ready/busy status can be determined after the start of internal write cycle by selecting the device (CS high) and polling the DO pin; DO low indicates that the write operation is not completed, while DO high indicates that the device is ready for the next instruction. If necessary, the DO pin may be placed back into a high impedance state during chip select by shifting a dummy "1" into the DI pin. The DO pin will enter the high impedance state on the rising edge of the clock (SK). Placing the DO pin into the high impedance state is recommended in applications where the DI pin and the DO pin are to be tied together to form a common DI/O pin.

The format for all instructions sent to the device is a logical "1" start bit, a 2-bit (or 4-bit) opcode, 8-bit address (an additional bit when organized X8) and for write operations a 16-bit data field (8-bit for X8 organizations). The instruction format is shown in Instruction Set table.

			Address		D	ata	
Instruction	Start Bit	Opcode	x8	x16	x8	x16	Comments
READ	1	10	A8-A0	A7-A0			Read Address AN – A0
ERASE	1	11	A8-A0	A7-A0			Clear Address AN – A0
WRITE	1	01	A8-A0	A7-A0	D7-D0	D15-D0	Write Address AN – A0
EWEN	1	00	11XXXXXXX	11XXXXXX			Write Enable
EWDS	1	00	00XXXXXXX	00XXXXXX			Write Disable
ERAL	1	00	10XXXXXXX	10XXXXXX			Clear All Addresses
WRAL	1	00	01XXXXXXX	01XXXXXX	D7-D0	D15-D0	Write All Addresses

#### **Table 9. INSTRUCTION SET**

#### Read

Upon receiving a READ command and an address (clocked into the DI pin), the DO pin of the CAT93C66 will come out of the high impedance state and, after sending an initial dummy zero bit, will begin shifting out the data addressed (MSB first). The output data bits will toggle on the rising edge of the SK clock and are stable after the specified time delay ( $t_{PD0}$  or  $t_{PD1}$ ).

For the CAT93C66, after the initial data word has been shifted out and CS remains asserted with the SK clock continuing to toggle, the device will automatically increment to the next address and shift out the next data word in a sequential READ mode. As long as CS is continuously asserted and SK continues to toggle, the device will keep incrementing to the next address automatically until it reaches to the end of the address space, then loops back to address 0. In the sequential READ mode, only the initial data word is preceeded by a dummy zero bit. All subsequent data words will follow without a dummy zero bit. The READ instruction timing is illustrated in Figure 3.

## Erase/Write Enable and Disable

The CAT93C66 powers up in the write disable state. Any writing after power-up or after an EWDS (erase/write disable) instruction must first be preceded by the EWEN (erase/write enable) instruction. Once the write instruction is enabled, it will remain enabled until power to the device is removed, or the EWDS instruction is sent. The EWDS instruction can be used to disable all CAT93C66 write and erase instructions, and will prevent any accidental writing or clearing of the device. Data can be read normally from the device regardless of the write enable/disable status. The EWEN and EWDS instructions timing is shown in Figure 4.

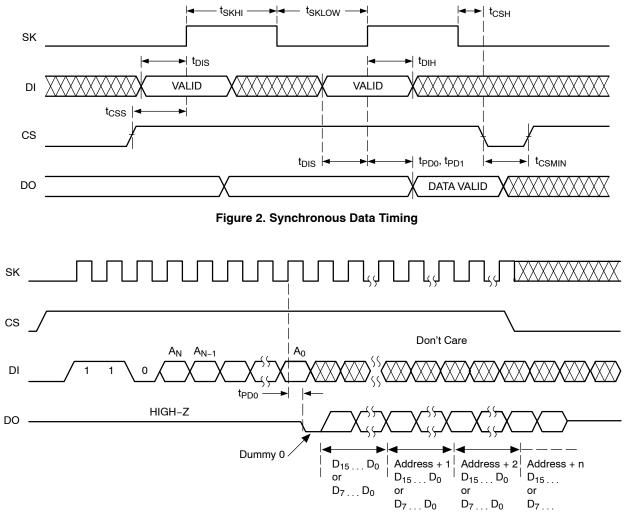


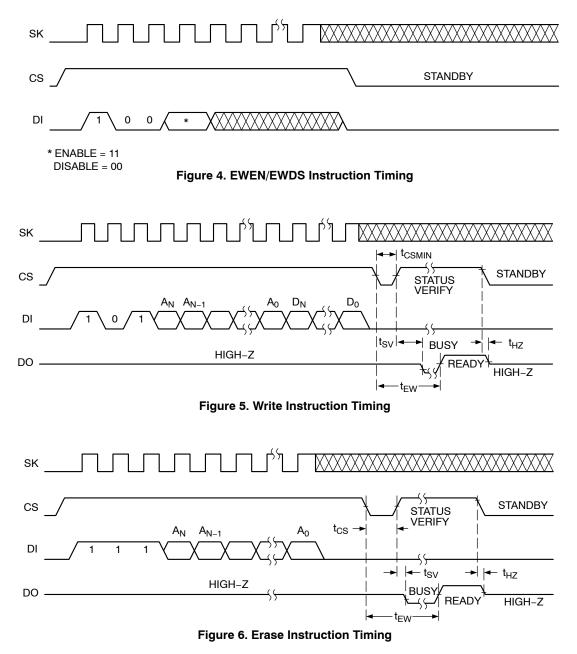
Figure 3. READ Instruction Timing

#### Write

After receiving a WRITE command (Figure 5), address and the data, the CS (Chip Select) pin must be deselected for a minimum of  $t_{CSMIN}$ . The falling edge of CS will start the self clocking clear and data store cycle of the memory location specified in the instruction. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the CAT93C66 can be determined by selecting the device and polling the DO pin. Since this device features Auto–Clear before write, it is NOT necessary to erase a memory location before it is written into.

#### Erase

Upon receiving an ERASE command and address, the CS (Chip Select) pin must be deasserted for a minimum of  $t_{CSMIN}$  (Figure 6). The falling edge of CS will start the self clocking clear cycle of the selected memory location. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the CAT93C66 can be determined by selecting the device and polling the DO pin. Once cleared, the content of a cleared location returns to a logical "1" state.

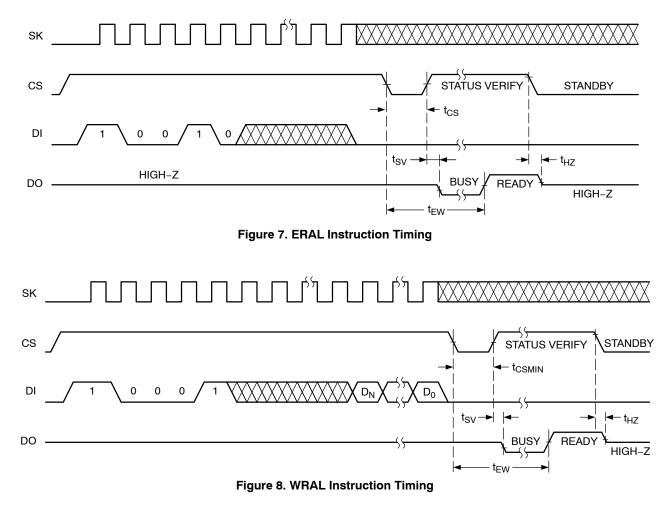


#### Erase All

Upon receiving an ERAL command (Figure 7), the CS (Chip Select) pin must be deselected for a minimum of  $t_{CSMIN}$ . The falling edge of CS will start the self clocking clear cycle of all memory locations in the device. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the CAT93C66 can be determined by selecting the device and polling the DO pin. Once cleared, the contents of all memory bits return to a logical "1" state.

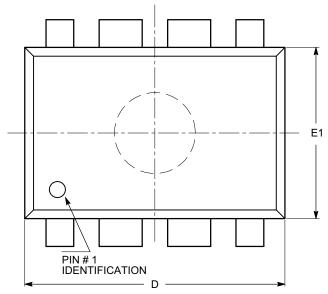
#### Write All

Upon receiving a WRAL command and data, the CS (Chip Select) pin must be deselected for a minimum of  $t_{CSMIN}$  (Figure 8). The falling edge of CS will start the self clocking data write to all memory locations in the device. The clocking of the SK pin is not necessary after the device has entered the self clocking mode. The ready/busy status of the CAT93C66 can be determined by selecting the device and polling the DO pin. It is not necessary for all memory locations to be cleared before the WRAL command is executed.



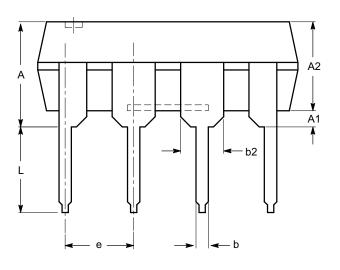
# PACKAGE DIMENSIONS

PDIP-8, 300 mils CASE 646AA-01 ISSUE A



SYMBOL	MIN	NOM	МАХ
А			5.33
A1	0.38		
A2	2.92	3.30	4.95
b	0.36	0.46	0.56
b2	1.14	1.52	1.78
с	0.20	0.25	0.36
D	9.02	9.27	10.16
E	7.62	7.87	8.25
E1	6.10	6.35	7.11
е	2.54 BSC		
eB	7.87		10.92
L	2.92	3.30	3.80

TOP VIEW

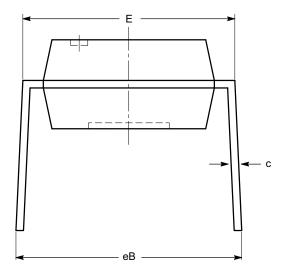


SIDE VIEW

## Notes:

(1) All dimensions are in millimeters.

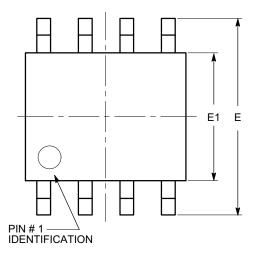
(2) Complies with JEDEC MS-001.



END VIEW

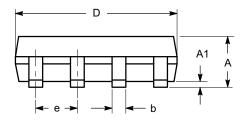
# PACKAGE DIMENSIONS

SOIC 8, 150 mils CASE 751BD-01 ISSUE O



SYMBOL	MIN	NOM	MAX
А	1.35		1.75
A1	0.10		0.25
b	0.33		0.51
с	0.19		0.25
D	4.80		5.00
E	5.80		6.20
E1	3.80		4.00
е		1.27 BSC	
h	0.25		0.50
L	0.40		1.27
θ	0°		8°

TOP VIEW

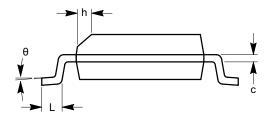


SIDE VIEW

## Notes:

(1) All dimensions are in millimeters. Angles in degrees.

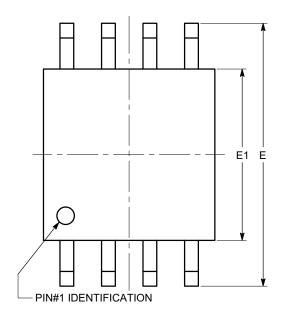
(2) Complies with JEDEC MS-012.



END VIEW

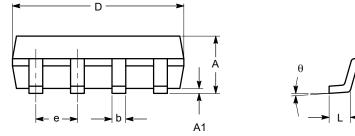
# PACKAGE DIMENSIONS

SOIC-8, 208 mils CASE 751BE-01 ISSUE O

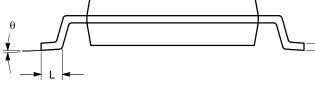


SYMBOL MIN NOM MAX А 2.03 A1 0.05 0.25 b 0.36 0.48 с 0.19 0.25 D 5.13 5.33 Е 7.75 8.26 E1 5.13 5.38 1.27 BSC е L 0.51 0.76 8° θ 0°

TOP VIEW



SIDE VIEW



END VIEW

С

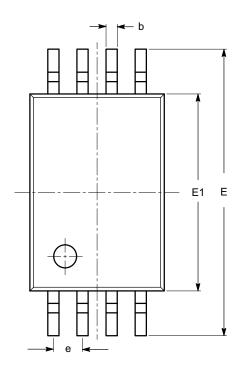
#### Notes:

(1) All dimensions are in millimeters. Angles in degrees.

(2) Complies with EIAJ EDR-7320.

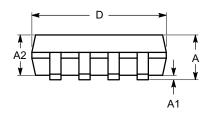
# PACKAGE DIMENSIONS

TSSOP8, 4.4x3 CASE 948AL-01 ISSUE O

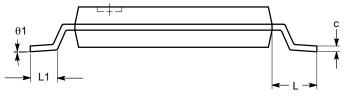


SYMBOL	MIN	NOM	MAX
А			1.20
A1	0.05		0.15
A2	0.80	0.90	1.05
b	0.19		0.30
с	0.09		0.20
D	2.90	3.00	3.10
E	6.30	6.40	6.50
E1	4.30	4.40	4.50
е		0.65 BSC	
L		1.00 REF	
L1	0.50	0.60	0.75
θ	0°		8°

#### TOP VIEW



SIDE VIEW



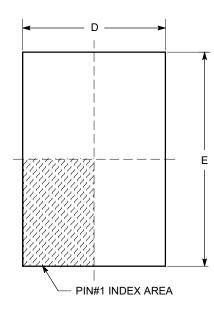
END VIEW

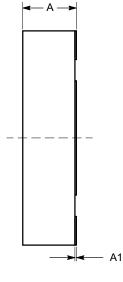
# Notes:

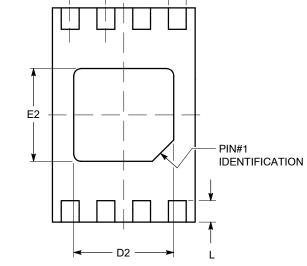
All dimensions are in millimeters. Angles in degrees.
Complies with JEDEC MO-153.

# PACKAGE DIMENSIONS

TDFN8, 2x3 CASE 511AK-01 ISSUE A







b

е

TOP VIEW

SIDE VIEW

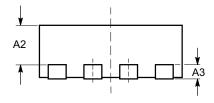
SYMBOL	MIN	NOM	MAX
А	0.70	0.75	0.80
A1	0.00	0.02	0.05
A2	0.45	0.55	0.65
A3	0.20 REF		
b	0.20	0.25	0.30
D	1.90	2.00	2.10
D2	1.30	1.40	1.50
E	2.90	3.00	3.10
E2	1.20	1.30	1.40
e	0.50 TYP		
L	0.20	0.30	0.40

#### Notes:

(1) All dimensions are in millimeters.

(2) Complies with JEDEC MO-229.

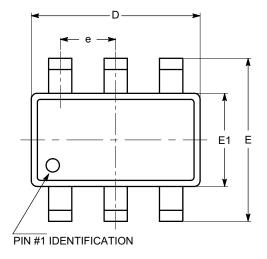
**BOTTOM VIEW** 



FRONT VIEW

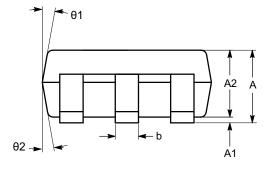
# PACKAGE DIMENSIONS

SOT-23, 6 Lead CASE 527AJ-01 ISSUE O



TOP VIEW

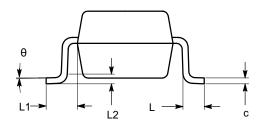
SYMBOL	MIN	NOM	MAX
А	0.90		1.45
A1	0.00		0.15
A2	0.90	1.15	1.30
b	0.30		0.50
с	0.08		0.22
D	2.90 BSC		
E	2.80 BSC		
E1	1.60 BSC		
е	0.95 BSC		
L	0.30	0.45	0.60
L1	0.60 REF		
L2	0.25 REF		
θ	0°	4°	8°
θ1	5°	10°	15°
θ2	5°	10°	15°



SIDE VIEW

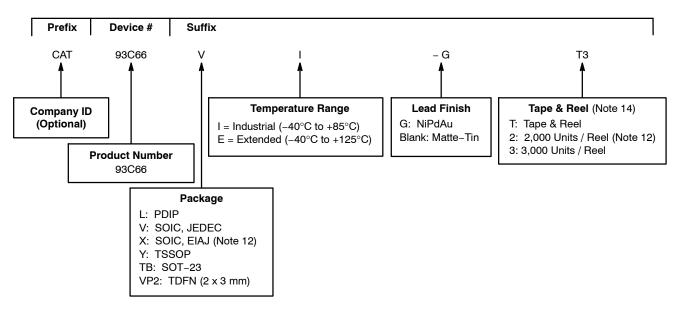
Notes:

All dimensions in millimeters. Angles in degrees.
Complies with JEDEC standard MO-178.



END VIEW

## **Example of Ordering Information**



9. All packages are RoHS-compliant (Lead-free, Halogen-free).

10. The standard lead finish is NiPdAu.

11. The device used in the above example is a CAT93C66VI-GT3 (SOIC, Industrial Temperature, NiPdAu, Tape & Reel, 3,000 units/Reel).

12. For SOIC, EIAJ (X) package the standard lead finish is Matte-Tin. This package is available in 2,000 pcs/reel, i.e. CAT93C66XI-T2.

13. For additional package and temperature options, please contact your nearest ON Semiconductor Sales office.

14. For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **ORDERING INFORMATION**

Orderable Part Numbers			
CAT93C66LI-G	CAT93C66LE-G		
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